

<b>Notice of References Cited</b>		Application/Control No. 10/564,463	Applicant(s)/Patent Under Reexamination DE LEEUW, VICTOR	
		Examiner STEPHEN HEPPERLE	Art Unit 3753	Page 1 of 1

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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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